

Yasuhiro Ogasahara

List of Publications by Year in descending order

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docs citations

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citing authors

#	ARTICLE	IF	CITATIONS
1	Yield and leakage current of organic thin-film transistor logic gates toward reliable and low-power operation of large-scale logic circuits for IoT nodes. Japanese Journal of Applied Physics, 2022, 61, SC1044.	1.5	3
2	Implementation of pseudo-linear feedback shift register-based physical unclonable functions on silicon and sufficient Challengeâ€Response pair acquisition using Built-In Self-Test before shipping. The Integration VLSI Journal, 2020, 71, 144-153.	2.1	6
3	Measurement and Modeling of Ambient-Air-Induced Degradation in Organic Thin-Film Transistor. IEEE Transactions on Semiconductor Manufacturing, 2020, 33, 216-223.	1.7	4
4	Recovery-aware bias-stress degradation model for organic thin-film transistors considering drain and gate bias voltages. Japanese Journal of Applied Physics, 2020, 59, SGGG08.	1.5	6
5	Organic Current Mirror PUF for Improved Stability Against Device Aging. IEEE Sensors Journal, 2020, 20, 7569-7578.	4.7	9
6	OCM-PUF: organic current mirror PUF with enhanced resilience to device degradation. , 2019, , .		5
7	Feasibility of a low-power, low-voltage complementary organic thin film transistor buskeeper physical unclonable function. Japanese Journal of Applied Physics, 2019, 58, SBBC03.	1.5	7
8	Mechanically and electrically robust metal-mask design for organic CMOS circuits. Japanese Journal of Applied Physics, 2018, 57, 04FL05.	1.5	6
9	An Experimental Design of Robust Current-mode Arbiter PUF using Organic Thin Film Transistors. , 2018, , .		0
10	Measurement and Modeling of Frequency Degradation of an oTFT Ring Oscillator. , 2018, , .		3
11	Prototype of USB stick-sized PUF module for authentication and key generation. , 2017, , .		1
12	A 65-nm SOTB implementation of a physically unclonable function and its performance improvement by body bias control. , 2017, , .		2
13	Implementation of pseudo linear feedback shift register physical unclonable function on silicon. , 2016, , .		5
14	Impacts of flexible V_{th} control, low process variability, and steep SS with low on-current of new structure transistors to ultra-low voltage designs. IEICE Electronics Express, 2015, 12, 20150460-20150460.	0.8	2
15	Low-power embedded read-only memory using atom switch and silicon-on-thin-buried-oxide transistor. Applied Physics Express, 2015, 8, 045201.	2.4	2
16	Standard cell implementation of buskeeper PUF with symmetric inverters and neighboring cells for passing randomness tests. , 2015, , .		3
17	A Silicon-on-Thin-Buried-Oxide CMOS Microcontroller with Embedded Atom-Switch ROM. IEEE Micro, 2015, 35, 13-23.	1.8	5
18	Measurement of V_{th} variation due to STI stress and inverse narrow channel effect at ultra-low voltage in a variability-suppressed process. , 2015, , .		0

#	ARTICLE	IF	CITATIONS
19	Reduction of overhead in adaptive body bias technology due to triple-well structure based on measurement and simulation. , 2015, , .		2
20	SOTB Implementation of a Field Programmable Gate Array with Fine-Grained Vt Programmability. Journal of Low Power Electronics and Applications, 2014, 4, 188-200.	2.0	8
21	Near-0.1V ultra-low voltage operation of SOTB 1M logic gates. , 2014, , .		1
22	More than an order of magnitude energy improvement of FPGA by combining 0.4V operation and Multi-Vt optimization of 20k body bias domains. , 2014, , .		4
23	Utility of high on-off ratio, high off resistance rewritable device to EEPROM for ultra-low voltage operation of steep subthreshold slope FETs. , 2014, , .		4
24	Resistivity-based modeling of substrate non-uniformity for low-resistivity substrate. IEICE Electronics Express, 2014, 11, 20130813-20130813.	0.8	0
25	The first SOTB implementation of Flex Power FPGA. , 2013, , .		5
26	Supply Noise Suppression by Triple-Well Structure. IEEE Transactions on Very Large Scale Integration (VLSI) Systems, 2013, 21, 781-785.	3.1	12
27	Measurement of on-chip I/O power supply noise and correlation verification between noise magnitude and delay increase due to SSO. , 2010, , .		0
28	All-Digital Ring-Oscillator-Based Macro for Sensing Dynamic Supply Noise Waveform. IEEE Journal of Solid-State Circuits, 2009, 44, 1745-1755.	5.4	33
29	Measurement and Analysis of Inductive Coupling Noise in 90 nm Global Interconnects. IEEE Journal of Solid-State Circuits, 2008, 43, 718-728.	5.4	7
30	Measurement of supply noise suppression by substrate and deep N-well in 90nm process. , 2008, , .		11
31	Dynamic supply noise measurement circuit composed of standard cells suitable for in-site SoC power integrity verification. , 2008, , .		2
32	Dynamic Supply Noise Measurement with All Digital Gated Oscillator for Evaluating Decoupling Capacitance Effect. , 2007, , .		5
33	Validation of a Full-Chip Simulation Model for Supply Noise and Delay Dependence on Average Voltage Drop With On-Chip Delay Measurement. IEEE Transactions on Circuits and Systems Part 2: Express Briefs, 2007, 54, 868-872.	2.2	31
34	Impact of well edge proximity effect on timing. , 2007, , .		0
35	Quantitative Prediction of On-Chip Capacitive and Inductive Crosstalk Noise and Tradeoff between Wire Cross-Sectional Area and Inductive Crosstalk Effect. IEICE Transactions on Fundamentals of Electronics, Communications and Computer Sciences, 2007, E90-A, 724-731.	0.3	2
36	Quantitative Prediction of On-chip Capacitive and Inductive Crosstalk Noise and Discussion on Wire Cross-Sectional Area Toward Inductive Crosstalk Free Interconnects. Proceedings - IEEE International Conference on Computer Design: VLSI in Computers and Processors, 2006, , .	0.0	2

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37	W-CDMA Channel Codec by Configurable Processors. Intelligent Automation and Soft Computing, 2006, 12, 317-329.	2.1	0
38	Measurement of Inductive Coupling Effect on Timing in 90nm Global Interconnects. , 2006, , .		4
39	Measurement results of delay degradation due to power supply noise well correlated with full-chip simulation. , 2006, , .		2